



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#6/Prc-and 2871  
a  
11/21/03

In the application of )

Group Art Unit 2871

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Tatiana Sergan, )

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**Certificate of Mailing under 37 CFR 1.8**

Serial No.: 10/085,973 )

Filed: February 28, 2002 )

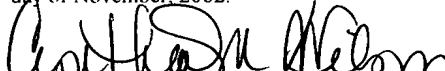
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I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Box Non-Fee Amendment, Commissioner for Patents, Washington, D.C. 20231 on this 22<sup>nd</sup> day of November, 2002.

  
Cynthia M. Wilson, Secretary to John J. Cunniff

**PRELIMINARY AMENDMENT**

COMMISSIONER FOR PATENTS

Washington, D.C. 20231

Sir:

Prior to examination, please preliminarily amend the above-identified application as follows.

**In the specification:**

Please replace the paragraph beginning on page 32, line 25 and extending to page 33, line 8, with the following paragraph:

a' The NH film was separated to the tilted aligned layer and the transparent substrate. And these characteristics were measured with the KOBRA-21ADH manufactured by Oji Measuring Machine Co., Ltd.. The transparent substrate had a retardation value:  $\Delta nd = (n_x - n_y) \times d = 4\text{nm}$ ,  $R_{th} = (n_x - n_z) \times d = 50\text{nm}$ . The other side, the tilted aligned layer had a retardation value:  $\Delta nd = 95\text{nm}$ ,  $R_{th} = 67\text{nm}$ , the average tilt angle  $\theta = 60^\circ$ , when an incidence ray angle was varied  $-50$  to  $50^\circ$  to the direction at the optical axis tilted.

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